5. CMOS Gate Characteristics

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VLSI Design
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Topics

- DC Response
- Logic Levels and Noise Margins
- Transient Response
- Delay Estimation

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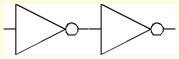
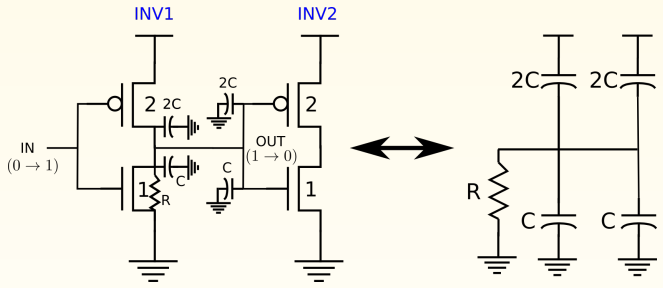
Review – Delay of an Inverter

Inverter is driving another identical inverter; delay is the time when the input changes to when the output changes. Note that the second inverter is just serving as a load for the first.



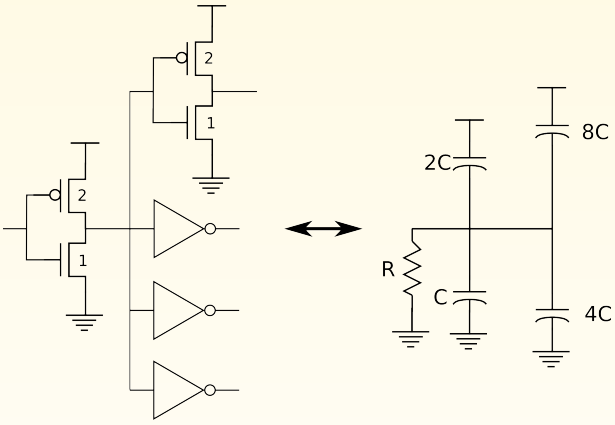
Simplifying assumptions

- Resistance of a unit transistor = R
- Gate capacitance of a unit transistor = C
- Source/drain capaticance of a unit transistor = C



Inverter Delay Estimate, Cont'd

Estimate the delay of an inverter driving 4 identical inverters –
Fanout-of-4 (FO4) delay
An important abstraction at higher levels of the design



d = 15RC

Transistor Behavior

Behavior in different situations (**increase**, **decrease**, or **not change**).

1. If the width of a transistor increases, the current will
2. If the length of a transistor increases, the current will
3. If the supply voltage of a chip increases, the maximum transistor current will
4. If the width of a transistor increases, its gate capacitance will
5. If the length of a transistor increases, its gate capacitance will
6. If the supply voltage of a chip increases, the gate capacitance of each transistor will

Transistor Behavior

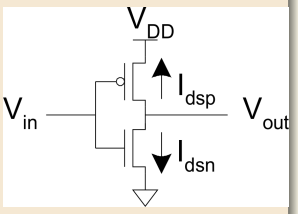
Behavior in different situations (**increase**, **decrease**, or **not change**).

1. If the width of a transistor increases, the current will **increase**
2. If the length of a transistor increases, the current will **decrease**
3. If the supply voltage of a chip increases, the maximum transistor current will **increase**
4. If the width of a transistor increases, its gate capacitance will **increase**
5. If the length of a transistor increases, its gate capacitance will **increase**
6. If the supply voltage of a chip increases, the gate capacitance of each transistor will **not change**

DC Response: V_{out} vs. V_{in} for a Gate

Study the response of Inverters

- When $V_{in} = 0 \implies V_{out} = V_{DD}$
- When $V_{in} = V_{DD} \implies V_{out} = 0$
- In between, V_{out} depends on transistor size and current
- By KCL, current must be such that $I_{dsn} = |I_{dsp}|$
- We could solve equations, but graphical solution gives more insight



Transistor Operation

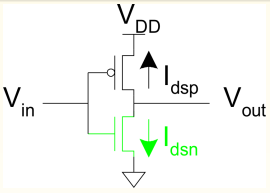
Current through transistor depends on the region of operation

- Need to identify for what V_{in} and V_{out} are nMOS and pMOS in Cutoff, Linear or Saturation

nMOS Operation

Cutoff	Linear	Saturated
$V_{gsn} < V_{tn}$	$V_{gsn} > V_{tn}$	$V_{gsn} > V_{tn}$
$V_{in} < V_{tn}$	$V_{in} > V_{tn}$	$V_{in} > V_{tn}$
	$V_{dsn} < V_{gsn} - V_{tn}$	$V_{dsn} > V_{gsn} - V_{tn}$
	$V_{out} < V_{in} - V_{tn}$	$V_{out} > V_{in} - V_{tn}$

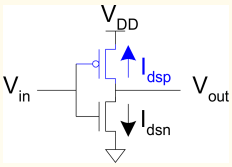
$$V_{gsn} = V_{in}$$
$$V_{dsn} = V_{out}$$



pMOS Operation

Cutoff	Linear	Saturated
$V_{gsp} > V_{tp}$	$V_{gsp} < V_{tp}$	$V_{gsp} < V_{tp}$
$V_{in} > V_{DD} + V_{tp}$	$V_{in} < V_{DD} + V_{tp}$	$V_{in} < V_{DD} + V_{tp}$
	$V_{dsp} > V_{gsp} - V_{tp}$	$V_{dsp} < V_{gsp} - V_{tp}$
	$V_{out} > V_{in} - V_{tp}$	$V_{out} < V_{in} - V_{tp}$

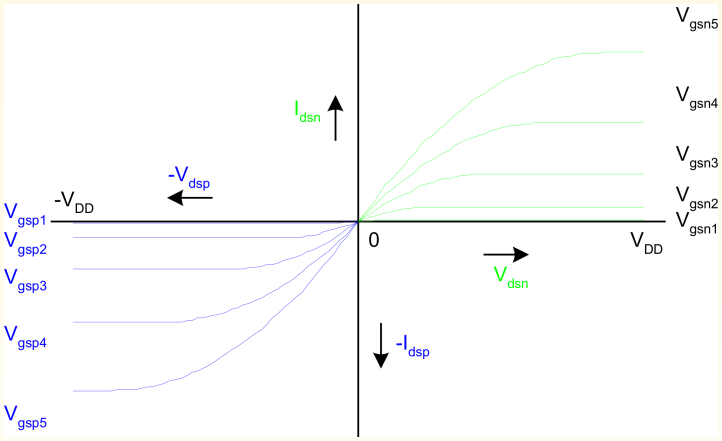
$$V_{gsp} = V_{in} - V_{DD}$$
$$V_{dsp} = V_{out} - V_{DD}$$
$$V_{tp} < 0$$



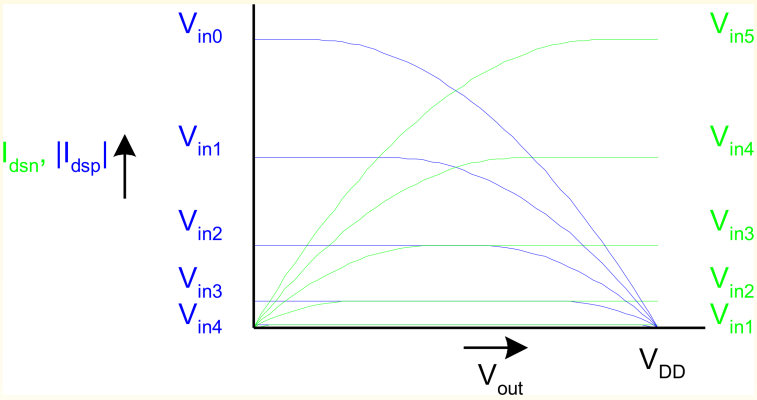
I-V Characteristics

Make pMOS wider than nMOS such that $\beta_n = \beta_p$

$\beta = \mu C_{ox} \frac{W}{L}$



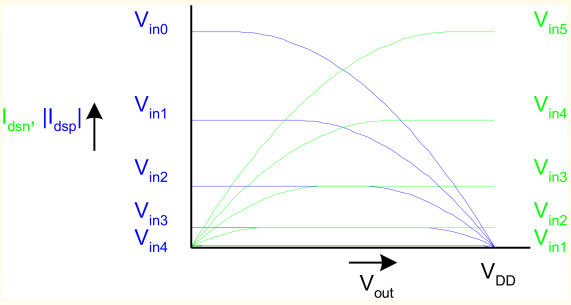
Current vs. V_{out}, V_{in}

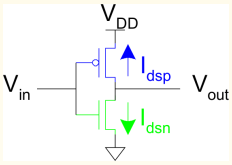


Load Line Analysis

To find the V_{out} for a given V_{in}

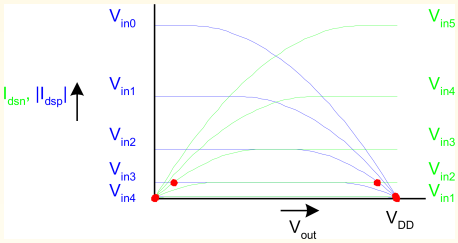
- For a given V_{in}, plot I_{dsn}, I_{dsp} vs. V_{out}
- V_{out} must be where |currents| are equal in the graph below

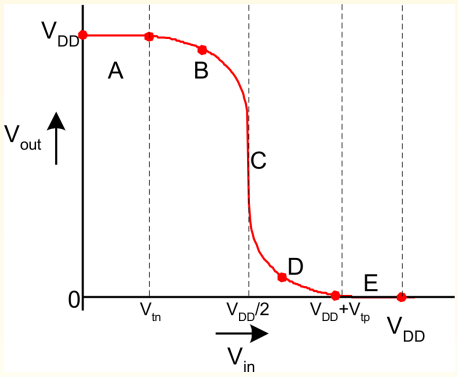




DC Transfer Curve

Transcribe points on to V_{in} vs. V_{out} plot

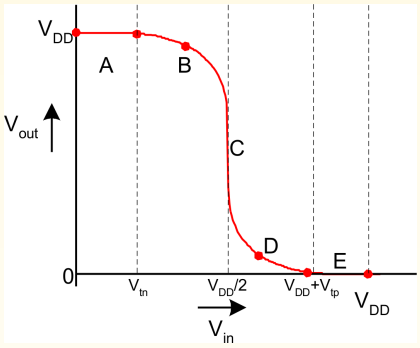




Operating Regions

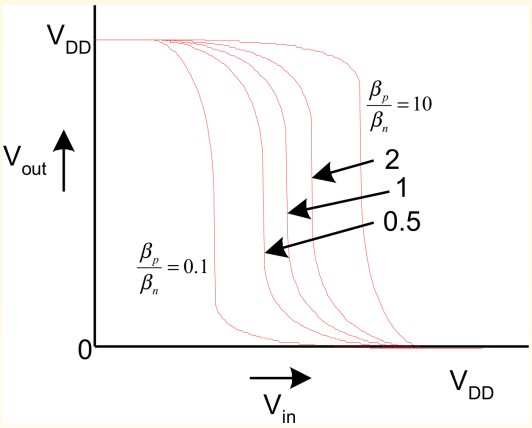
Revisit transistor operating regions

Region	nMOS	pMOS
A	Cutoff	Linear
B	Saturation	Linear
C	Saturation	Saturation
D	Linear	Saturation
E	Linear	Cutoff



Beta Ratio

- If $\beta_p/\beta_n \neq 1$, switching point will move from $V_{DD}/2$
- Called **skewed** gate

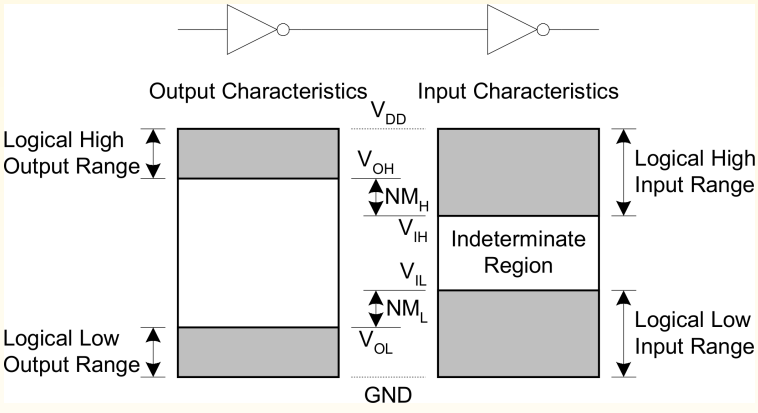


Analysis of more complex gates

- **Collapse into equivalent inverter**

Noise Margins

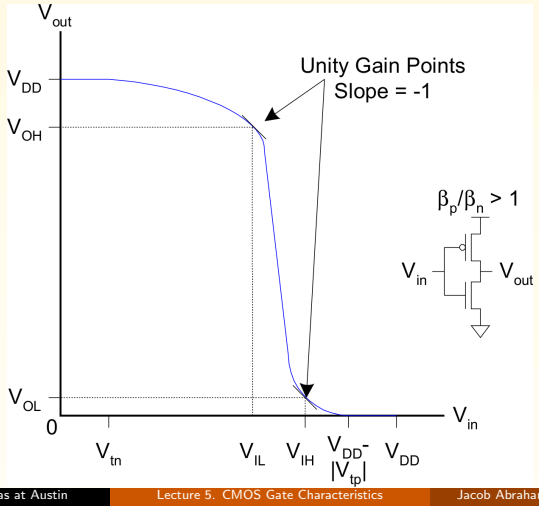
How much noise can a gate input see before it does not recognize the input?



Logic Levels

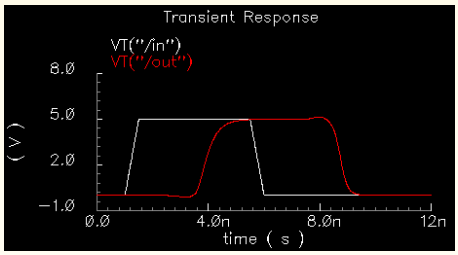
To maximize noise margins

- Select logic levels at unity gain point of DC transfer characteristic



Transient Response

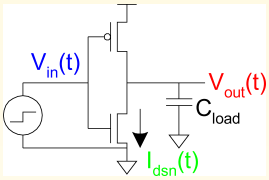
- **DC analysis** gives the V_{out} if V_{in} is constant
- **Transient analysis** tells us V_{out} as V_{in} changes
- Input is usually considered to be a step or ramp (from 0 to V_{DD} or vice-versa)

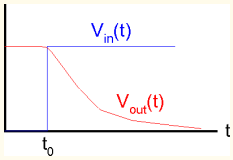


Inverter Step Response

Find the step response of an inverter driving a load capacitance

- $V_{in}(t) = u(t - t_0)V_{DD}$
- $V_{out}(t < t_0) = V_{DD}$
- $\frac{dV_{out}(t)}{dt} = -\frac{I_{dsn}(t)}{C_{load}}$

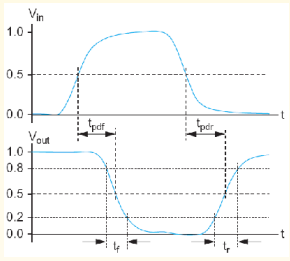




$$I_{dsn}(t) = \begin{cases} 0 & t \le t_0 \\ \frac{\beta}{2}(V_{DD} - V)^2 & V_{out} > V_{DD} - V_t \\ \beta\left(V_{DD} - V_t - \frac{V_{out}(t)}{2}\right)V_{out}(t) & V_{out} < V_{DD} - V_t \end{cases}$$

Delay Definitions

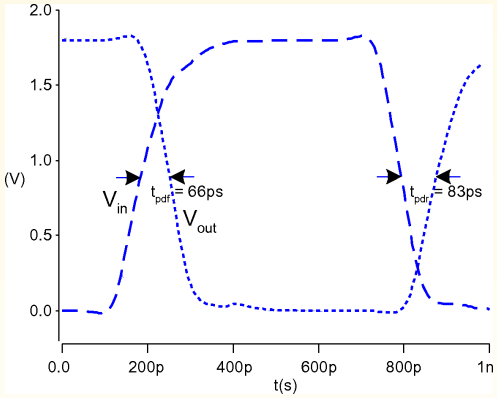
- t_{pdr}: rising propagation delay
  - From input to rising output crossing $V_{DD}/2$
- t_{pdf}: falling propagation delay
  - From input to falling output crossing $V_{DD}/2$
- t_{pd}: average propagation delay
  - $t_{pd} = (t_{pdr} + t_{pdf})/2$
- t_r: rise time
  - From output crossing $0.2\ V_{DD}$ to $0.8\ V_{DD}$
- t_f: fall time
  - From output crossing $0.8\ V_{DD}$ to $0.2\ V_{DD}$



- t_{cdr}: rising contamination delay
  - Minimum time from input to rising output crossing $V_{DD}/2$
- t_{cdf}: falling contamination delay
  - Minimum time from input to falling output crossing $V_{DD}/2$
- t_{cd}: average contamination delay
  - $t_{cd} = (t_{cdr} + t_{cdf})/2$

Simulated Inverter Delay

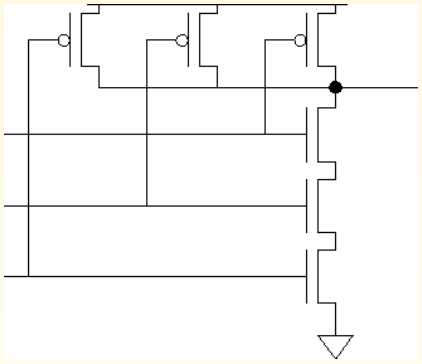
- Solving differential equations by hand too hard
- SPICE simulator solves equations numerically
  - Uses more accurate I-V models too!
- But simulations take time to write



Delay Estimation

- We would like to be able to easily estimate delay
  - Not as accurate as simulation
  - But easier to ask "what if ..."?
- The step response usually looks like a first order RC response with a decaying exponential
- Use RC delay models to estimate delay
  - C = total capacitance on output node
  - Use **effective resistance** R
  - So that t_{pd} **= RC**
- Characterize transistors by finding their effective R
  - Depends on average current as gate switches

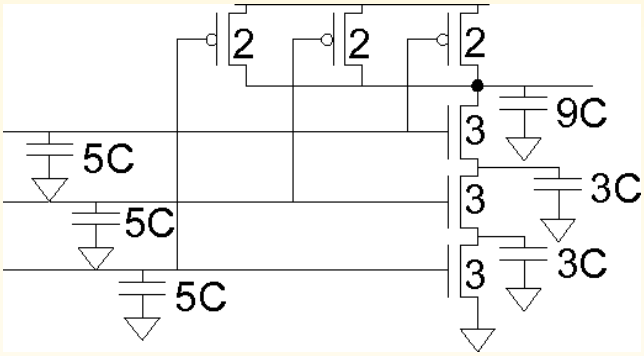
Example: Sizing 3-Input NAND Gate for Equal Rise and Fall Times



Determine the transistor widths to achieve effective rise and fall resistances (times) equal to that of a unit inverter R

Annotate the 3-input NAND gate with gate and diffusion capacitances

Example 3-Input NAND Gate



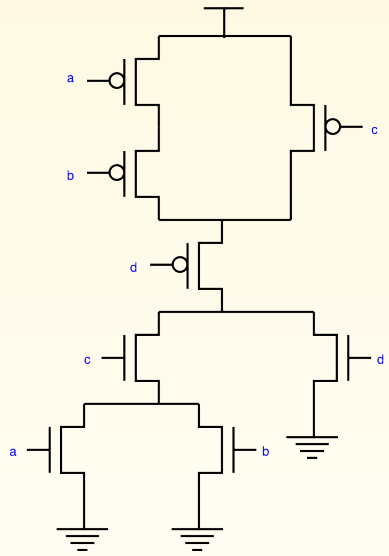
Determine the transistor widths to achieve effective rise and fall resistances (times) equal to that of a unit inverter R

Annotate the 3-input NAND gate with gate and diffusion capacitances

Example: Sizing Complex Gate

Size the transistors in the circuit below so that it has the same drive strength, in the worst case, as an inverter that has PW = 5 and NW = 3.
Use the smallest widths possible to achieve this ratio.

Note: if there are multiple paths through a transistor, use the size for the "worst-case" input combination.

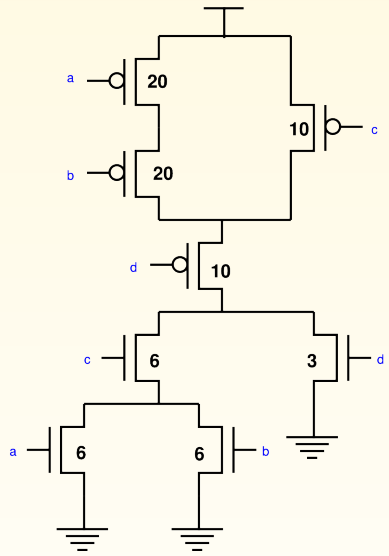


Example: Sizing Complex Gate

Size the transistors in the circuit below so that it has the same drive strength, in the worst case, as an inverter that has PW = 5 and NW = 3.
Use the smallest widths possible to achieve this ratio.

This solution does NOT use the smallest widths

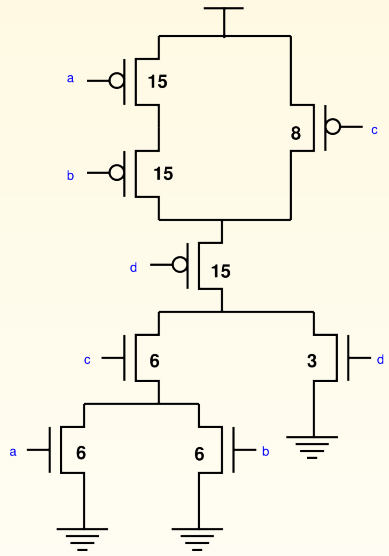
Note: if there are multiple paths through a transistor, use the size for the "worst-case" input combination.



Example: Sizing of Complex Gate – Better Solution

Size the transistors in the circuit below so that it has the same drive strength, in the worst case, as an inverter that has PW = 5 and NW = 3.
Use the smallest widths possible to achieve this ratio.

Note: if there are multiple paths through a transistor, use the size for the "worst-case" input combination.

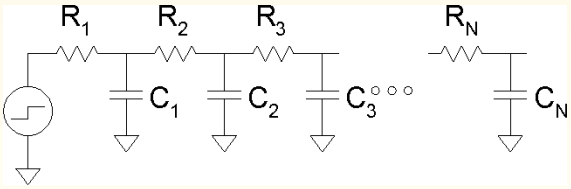


Elmore Delay

Finding the delay of ladder networks

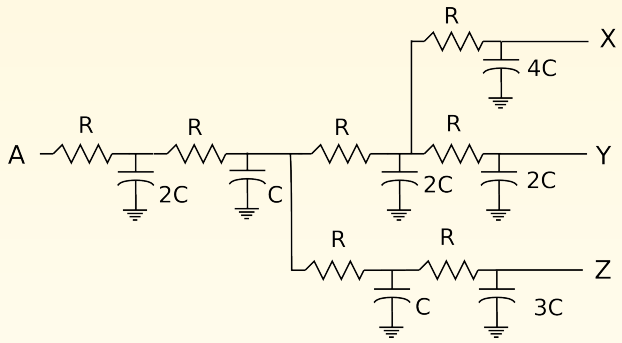
- ON transistors look like resistors
- Pullup or pulldown network modeled as RC ladder
- Elmore delay of RC ladder

$$t_{pd} = \sum_{nodes\ i} R_{i-to-source} C_i$$
$$= R_1C_1 + (R_1 + R_2)C_2 + \ldots + (R_1 + R_2 + \ldots + R_N)C_N$$



NOTE: C_i includes all the "off-path" capacitance on nodes that are connected to node i

Example: Elmore Delay Calculation

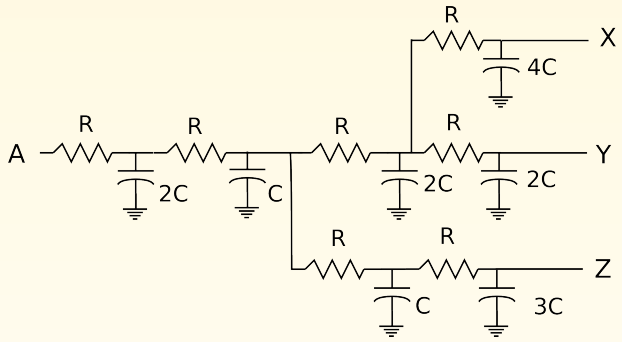


Delay from A to X:

Delay from A to Y:

Delay from A to Z:

Example: Elmore Delay Calculation, Cont'd



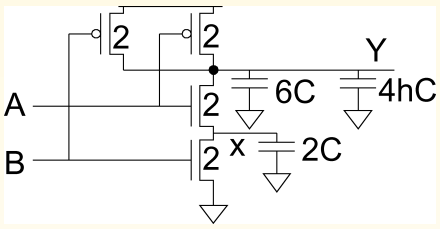
Delay from A to X: 40RC

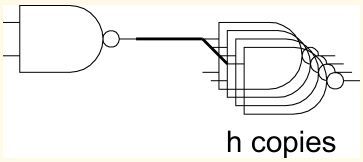
Delay from A to Y: 38RC

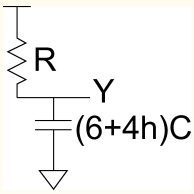
Delay from A to Z: 35RC

Example: Delay of 2-Input NAND Using Elmore Formulation

Estimate **rising** and falling propagation delays of a 2-input NAND driving h identical gates



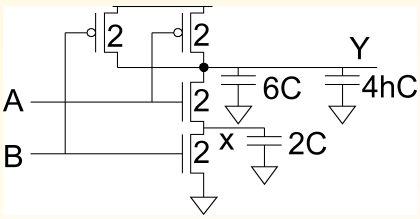


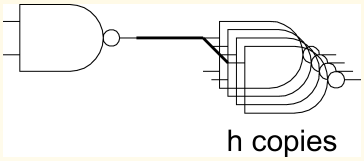


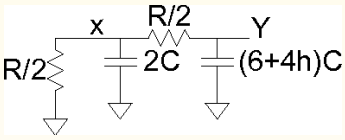
$$t_{pdr} = (6 + 4h)RC$$

Example: Delay of 2-Input NAND Using Elmore Formulation

Estimate rising and **falling** propagation delays of a 2-input NAND driving h identical gates



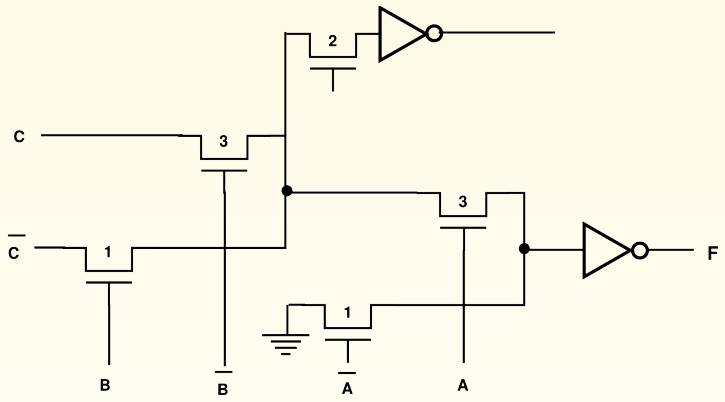




$$t_{pdf} = (2C)\frac{R}{2} + \left[(6 + 4h)C\right]\left(\frac{R}{2} + \frac{R}{2}\right)$$
$$= (7 + 4h)RC$$

Example of Elmore Delay Calculation

Calculate the Elmore delay from C to F in the circuit. The widths of the pass transistors are shown, and the inverters have minimum-sized transistors



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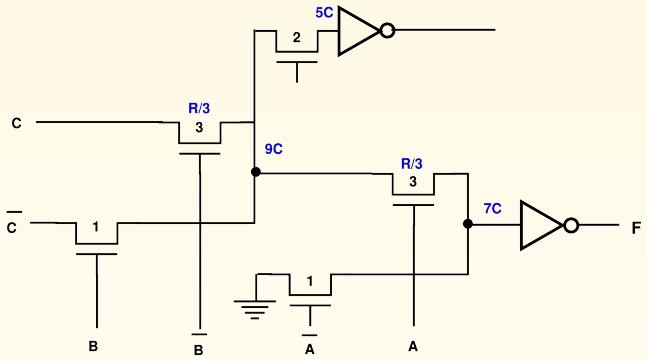
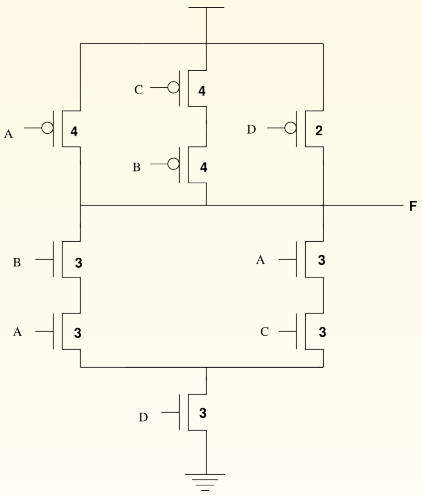


$$Delay = \frac{R}{3}9C + \frac{R}{3}5C + \left(\frac{R}{3} + \frac{R}{3}\right)7C + 3RC = 12.33RC$$

Another Example: Elmore Delay Calculation

Use the Elmore delay approximation to find the *worst-case* rise and fall delays at output F for the following circuit. The gate sizes of the transistors are shown in the figure. Assume NO sharing of diffusion regions, and the worst-case conditions for the initial charge on a node.



Input for worst-case rise delay =

Worst-case rise delay =

Input for worst-case fall delay =

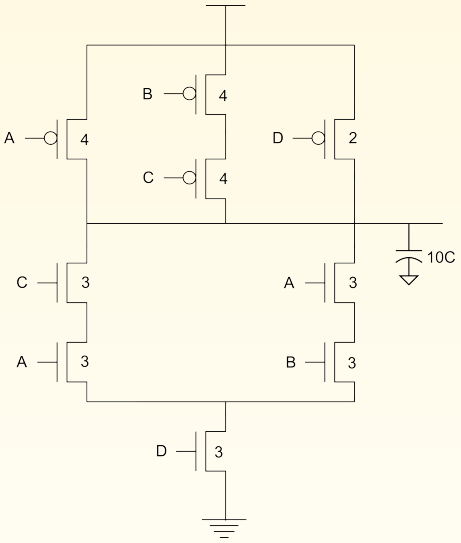
Worst-case fall delay =

Delay with Different Input Sequences

Find the delays for the given input transitions (gate sizes shown in figure)

Assumptions: diffusion capacitance is equal to the gate capacitance, the resistance of an nMOS transistor with unit width is R and the resistance of a pMOS transistor with width 2 is also R, and NO sharing of diffusion regions

Off-path capacitances can contribute to delay, and if a node does not need to be charged (or discharged), its capacitance can be ignored



$$ABCD = 0101 \rightarrow ABCD = 1101$$

$$ABCD = 1111 \rightarrow ABCD = 0111$$

$$ABCD = 1010 \rightarrow ABCD = 1101$$

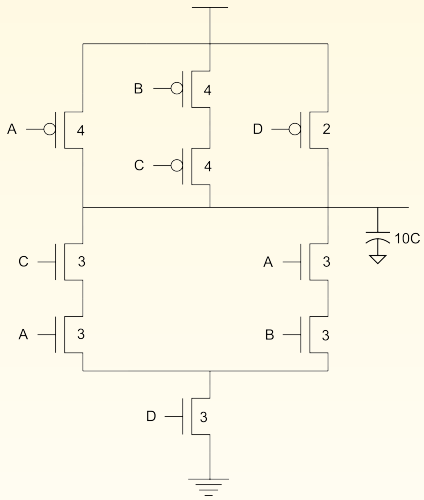
Delay with Different Input Sequence, Cont'd

Look at the charges on the nodes at the end of the first input of the sequence; only the capacitances of the nodes which would change with the second vector need to be considered

$ABCD = 0101 \rightarrow$
$ABCD = 1101;$
Delay = 36RC

$ABCD = 1111 \rightarrow$
$ABCD = 0111;$
Delay = 16RC

$ABCD = 1010 \rightarrow$
$ABCD = 1101;$
Delay = 43RC



Delay Components

Delay has two parts

Parasitic Delay

- 6 or 7 RC
- Independent of Load

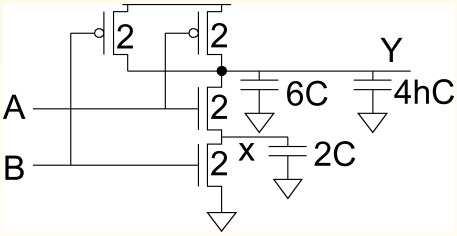
Effort Delay

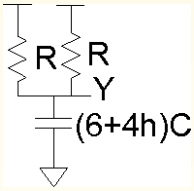
- 4h RC
- Proportional to load capacitance

Contamination Delay

Minimum (Contamination) Delay

- Best-case (contamination) delay can be substantially less than propagation delay
- Example, If both inputs fall simultaneously
- Important for "hold time" (will see later in the course)

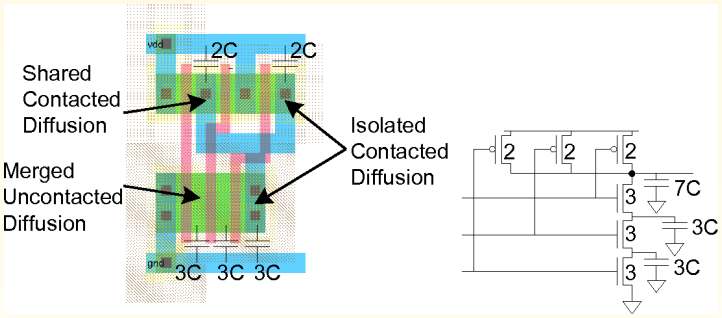




$$t_{cdr} = (3+2h)RC$$

Diffusion Capacitance

- We assumed contacted diffusion on every source/drain
- Good layout minimizes diffusion area
- Example, NAND3 layout shares one diffusion contact
  - Reduces output capacitance by 2C
  - Merged uncontacted diffusion might help too



These general observations can be used for initial estimates of area and performance – using tools to extract parasitics will provide more accurate results for a particular technology